

HQ:CSC37/tipless/Cr-Au

Tipless AFM Probe with 3 Different Gold Coated Contact Mode AFM Cantilevers

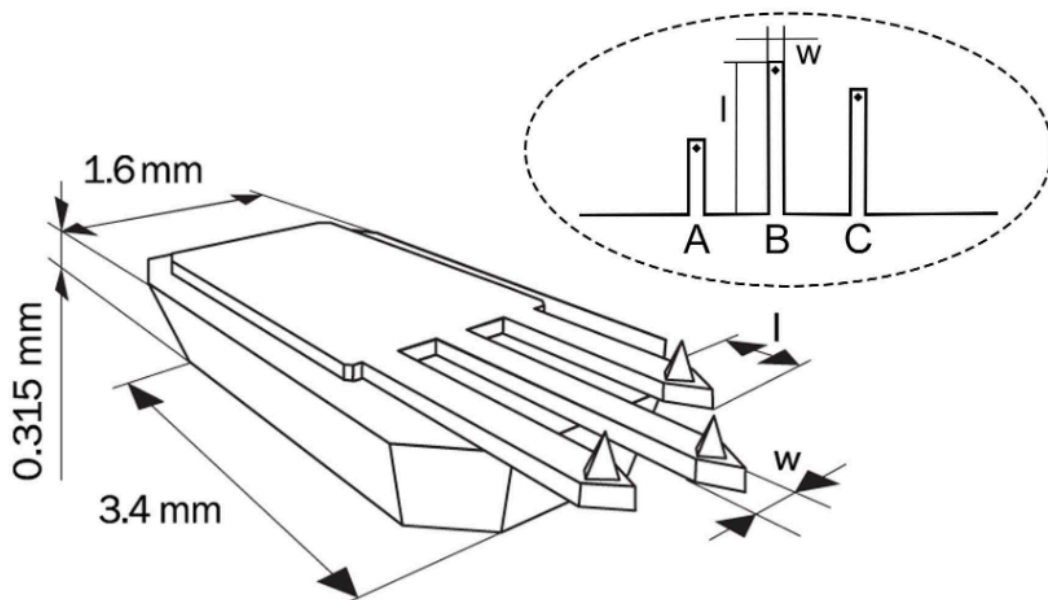
AFM probes of the HQ:CSC37 series have three different tipless contact mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

The overall 30 nm Au coating with 20 nm Cr sublayer is electrically conductive and chemically inert. It also enhances the laser reflectivity of the AFM cantilevers in air and liquids. The coating may cause AFM cantilever bending up to 3° .

Coating

Gold Overall



AFM Probe Specifications

AFM Tip

| SHAPE |
|---------|
| Tipless |

AFM Cantilever

| CANTILEVER | SHAPE | FORCE CONST. | RES. FREQ. | LENGTH | WIDTH | THICKNESS |
|--------------|-------|-----------------------------|--------------------------|--|---|--|
| Cantilever A | Beam | 0.8 N/m (0.3 – 2 N/m)* | 40 kHz (30 – 55 kHz)* | 250 μm (1 – 255 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever B | Beam | 0.3 N/m (0.1 – 0.6 N/m)* | 20 kHz (15 – 30 kHz)* | 350 μm (1 – 355 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever C | Beam | 0.4 N/m (0.1 – 1 N/m)* | 30 kHz (20 – 40 kHz)* | 300 μm (1 – 305 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |

* typical values